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J. C. H.
11-19-03

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors: Chian-Min Richard Ho et al.
Assignee: OIN Design Automation, Inc.
Title: Method for automatically searching for defects in a description of a circuit
Serial No.: 09/849,005 Filing Date: May 4, 2001
Examiner: Frejd, Russell Warren Group Art Unit: 2123
Docket No.: 0IN006-1C US Confirmation No: 1848

Santa Clara, California
October 10, 2003

COMMISSIONER FOR PATENTS
P.O. BOX 1450
ALEXANDRIA VA 22313-1450

**INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR §1.97(c)**

Dear Sir:

Pursuant to 37 C.F.R. § 1.56, §1.97 and §1.98, the Applicants submit for consideration in the above-identified patent application the documents listed on the accompanying Forms PTO-1449. The Forms PTO-1449 are submitted in two parts, namely Part A of 3 sheets and Part B of 24 sheets. Copies of 28 documents cited in Part A are also submitted herewith (but references 9, 10 and 11 are not being submitted and the Examiner is requested to obtain them from the USPTO files of the parent application). The Examiner is requested to make all these documents of record. Applicants would appreciate the Examiner initialing and returning the all the Forms PTO-1449, indicating that the information has been considered and made of record herein.

This Information Disclosure Statement is submitted pursuant to 37 CFR §1.97(c) as it is after receipt of a first Office Action on the merits but before mailing of a final Action or Notice of Allowance. Accordingly, a fee is required pursuant to 37 CFR §1.17(p). A Fee Transmittal form (PTO/SB/17) is attached to this submission.

In addition, Applicants submit for the Examiner's consideration the following list of co-owned patents and application, cited by serial number, first named inventor and



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filing date. The Applicants presume that the Examiner has access to and will review the co-owned patents and applications and the files thereof for any office actions, amendments or other materials that may be relevant to the patentability of the claims of the present application. For any such U.S. patent application(s) that are currently pending, the Applicants further presume that the Examiner will consider any future office actions, amendments or other materials in the file thereof that may be relevant to the patentability of the claims herein. **If the Applicants' understanding in this regard is not correct, please notify the undersigned so that copies of any such documents can be submitted to the Examiner**

	Serial No.:	First Named Inventor	Filing Date:
1.	08/955,329	Ly et al.	10/20/1997
2.	09/635,598	Ly et al.	8/9/2000
3.	10/348,116	Ly et al.	1/20/2003
4.	08/954,765	Ho et al.	10/20/1997

The information contained in this Information Disclosure Statement under is to the best of my knowledge and is not to be construed as a representation that: (i) a complete search has been made; (ii) additional information material to the examination of this application does not exist; (iii) the information, protocols, results and the like reported by third parties are accurate or enabling; or (iv) the above information constitutes prior art to the subject invention.

**Via Express Mail Label No.
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Respectfully submitted,

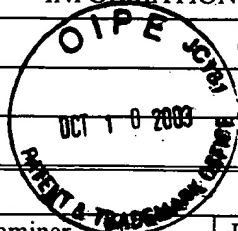


Omkar K. Suryadevara
Attorney for Applicants
Reg. No. 36,320

U.S. Department of Commerce, Patent and Trademark Office					Atty Docket No.		Serial No.	
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U.S. Patent Documents								
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	AA	5,555,270	9/10/96	Sun et al.	371	27		
	AB	5,630,051	5/13/97	Sun et al.	395	183.08		
	AC	5,600,787	2/4/97	Underwood et al.	395	183.06		
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	AI	Windley, Phillip J., "Formal Modeling and Verification of Microprocessors", IEEE Transactions on Computers, Vol. 44, No. 1, January 1995, pp. 54-72.						
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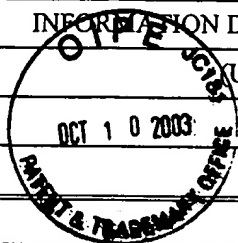
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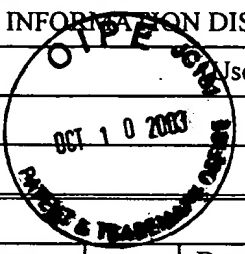
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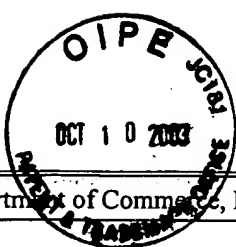
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	AJ	Malley, Charles, et al., "Logic Verification Methodology for Power PC TM Microprocessors", 32 nd Design Automation Conference, San Francisco, CA, June 12-16, 1995, pp. 234-240.							
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PART "B"

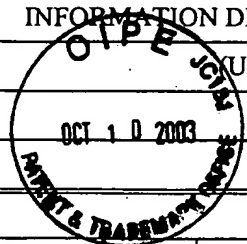
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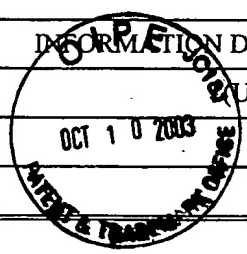


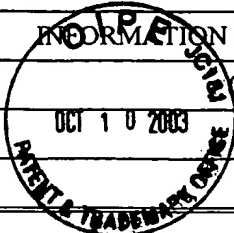
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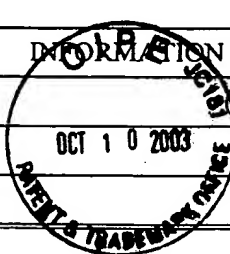
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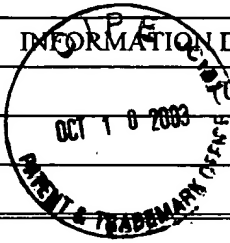
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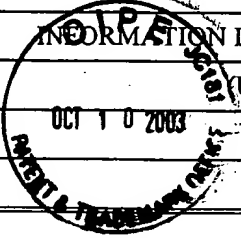
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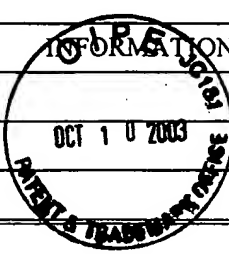
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)					Applicants: Chian-Min Ho et al.			
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U.S. Patent Documents								
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	AA							
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Foreign Patent Documents								
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	AG							
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